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## High Speed PT IGBT

POWER MOS $8^{\circledR}$ is a high speed Punch－Through switch－mode IGBT．Low $\mathrm{E}_{\text {off }}$ is achieved through leading technology silicon design and lifetime control processes．A reduced $\mathrm{E}_{\text {off }}$－ $\mathrm{V}_{\mathrm{CE}(\mathrm{ON})}$ tradeoff results in superior efficiency compared to other IGBT technologies．Low gate charge and a greatly reduced ratio of $\mathrm{C}_{\text {res }} / \mathrm{C}_{\text {ies }}$ provide excellent noise immunity，short delay times and simple gate drive．The intrinsic chip gate resistance and capacitance of the poly－silicone gate structure help control di／dt during switching，resulting in low EMI，even when switching at high frequency．


## FEATURES

－Fast switching with low EMI
－Very Low $E_{\text {off }}$ for maximum efficiency
－Ultra low $\mathrm{C}_{\text {res }}$ for improved noise immunity
－Low conduction loss
－Low gate charge
－Increased intrinsic gate resistance for low EMI
－RoHS compliant

## TYPICAL APPLICATIONS

－ZVS phase shifted and other full bridge
－Half bridge
－High power PFC boost
－Welding
－UPS，solar，and other inverters
－High frequency，high efficiency industrial

## Absolute Maximum Ratings

| Symbol | Parameter | Ratings | Unit |
| :---: | :---: | :---: | :---: |
| $V_{\text {ces }}$ | Collector Emitter Voltage | 600 | V |
| $\mathrm{I}_{1}$ | Continuous Collector Current＠ $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 96 | A |
| $\mathrm{I}_{\mathrm{c} 2}$ | Continuous Collector Current＠ $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ | 54 |  |
| $\mathrm{I}_{\text {cm }}$ | Pulsed Collector Current ${ }^{1}$ | 161 |  |
| $V_{G E}$ | Gate－Emitter Voltage ${ }^{2}$ | $\pm 30$ | V |
| $\mathrm{P}_{\mathrm{D}}$ | Total Power Dissipation＠ $\mathrm{C}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 416 | W |
| SSOA | Switching Safe Operating Area＠ $\mathrm{T}_{\mathrm{J}}=150^{\circ} \mathrm{C}$ | 161A＠600V |  |
| $\mathrm{T}_{\mathrm{J}}, \mathrm{T}_{\text {STG }}$ | Operating and Storage Junction Temperature Range | －55 to 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | Lead Temperature for Soldering：0．063＂from Case for 10 Seconds | 300 |  |

Static Characteristics $\quad \mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ unless otherwise specified

| Symbol | Parameter | Test Conditions |  | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {BR（CES }}$ | Collector－Emitter Breakdown Voltage | $\mathrm{V}_{G E}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{C}}=1.0 \mathrm{~mA}$ |  | 600 |  |  | V |
| $V_{\text {CE（on）}}$ | Collector－Emitter On Voltage | $\begin{gathered} V_{G E}=15 \mathrm{~V}, \\ I_{C}=32 \mathrm{~A} \end{gathered}$ | $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ |  | 2.0 | 2.5 |  |
|  |  |  | $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ |  | 1.9 |  |  |
| $\mathrm{V}_{\text {GE（th）}}$ | Gate Emitter Threshold Voltage | $\mathrm{V}_{\text {GE }}=\mathrm{V}_{\text {CE }}, \mathrm{I}_{\mathrm{C}}=1 \mathrm{~mA}$ |  | 3 | 4.5 | 6 |  |
| $\mathrm{I}_{\text {ces }}$ | Zero Gate Voltage Collector Current | $\mathrm{V}_{\text {CE }}=600 \mathrm{~V}$ ， | $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ |  |  | 250 | $\mu \mathrm{A}$ |
|  |  | $V_{G E}=0 \mathrm{~V}$ | $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ |  |  | 2500 |  |
| $\mathrm{I}_{\text {GES }}$ | Gate－Emitter Leakage Current | $\mathrm{V}_{\mathrm{GS}}= \pm 30 \mathrm{~V}$ |  |  |  | $\pm 100$ | nA |

## Thermal and Mechanical Characteristics

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| $R_{\text {eJC }}$ | Junction to Case Thermal Resistance | - | - | .3 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{W}_{\mathrm{T}}$ | Package Weight | - | 5.9 | - | g |
| Torque | Mounting Torque（TO－247 Package），4－40 or M3 screw |  |  | 10 | in•lbf |

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| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {ies }}$ | Input Capacitance | Capacitance$\begin{gathered} V_{G E}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{CE}}=25 \mathrm{~V} \\ \mathrm{f}=1 \mathrm{MHz} \end{gathered}$ |  | 4130 |  | pF |
| $\mathrm{C}_{\text {oes }}$ | Output Capacitance |  |  | 350 |  |  |
| $\mathrm{C}_{\text {res }}$ | Reverse Transfer Capacitance |  |  | 45 |  |  |
| $Q_{g}{ }^{3}$ | Total Gate Charge | Gate Charge$\begin{gathered} V_{G E}=15 \mathrm{~V} \\ V_{C E}=300 \mathrm{~V} \\ \mathrm{I}_{\mathrm{C}}=32 \mathrm{~A} \end{gathered}$ |  | 158 |  | $n \mathrm{C}$ |
| $\mathrm{Q}_{\mathrm{ge}}$ | Gate-Emitter Charge |  |  | 26 |  |  |
| $\mathrm{Q}_{\mathrm{gc}}$ | Gate- Collector Charge |  |  | 52 |  |  |
| SSOA | Switching Safe Operating Area | $\begin{gathered} \mathrm{T}_{\mathrm{J}}=150^{\circ} \mathrm{C}, \mathrm{R}_{\mathrm{G}}=4.7 \Omega^{4}, \mathrm{~V}_{\mathrm{GE}}=15 \mathrm{~V}, \\ \mathrm{~L}=100 \mathrm{uH}, \mathrm{~V}_{\mathrm{CE}}=600 \mathrm{~V} \end{gathered}$ | 161 |  |  | A |
| $\mathrm{t}_{\text {d(on) }}$ | Turn-On Delay Time | Inductive Switching $\left(25^{\circ} \mathrm{C}\right)$$\begin{gathered} \mathrm{V}_{\mathrm{CC}}=400 \mathrm{~V} \\ \mathrm{~V}_{\mathrm{GE}}=15 \mathrm{~V} \\ \mathrm{I}_{\mathrm{C}}=32 \mathrm{~A} \\ \mathrm{R}_{\mathrm{G}}=4.7 \Omega^{4} \\ \mathrm{~T}_{\mathrm{J}}=+25^{\circ} \mathrm{C} \end{gathered}$ |  | 17 |  | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Current Rise Time |  |  | 20 |  |  |
| $\mathrm{t}_{\text {d(off) }}$ | Turn-Off Delay Time |  |  | 112 |  |  |
| $\mathrm{t}_{\mathrm{f}}$ | Current Fall Time |  |  | 86 |  |  |
| $\mathrm{E}_{\text {on2 }}$ | Turn-On Switching Energy |  |  | 534 |  | $\mu \mathrm{J}$ |
| $\mathrm{E}_{\text {off }}{ }^{6}$ | Turn-Off Switching Energy |  |  | 466 |  |  |
| $\mathrm{t}_{\text {don }}$ | Turn-On Delay Time | Inductive Switching $\left(125^{\circ} \mathrm{C}\right)$$\begin{gathered} V_{C C}=400 \mathrm{~V} \\ V_{G E}=15 \mathrm{~V} \\ \mathrm{I}_{\mathrm{C}}=32 \mathrm{~A} \\ \mathrm{R}_{\mathrm{G}}=4.7 \Omega^{4} \\ \mathrm{~T}_{\mathrm{J}}=+125^{\circ} \mathrm{C} \\ \hline \end{gathered}$ |  | 16 |  | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Current Rise Time |  |  | 21 |  |  |
| $\mathrm{t}_{\text {doff) }}$ | Turn-Off Delay Time |  |  | 146 |  |  |
| $\mathrm{t}_{\mathrm{f}}$ | Current Fall Time |  |  | 145 |  |  |
| $\mathrm{E}_{\text {on2 }}$ | Turn-On Switching Energy |  |  | 891 |  | $\mu \mathrm{J}$ |
| $\mathrm{E}_{\text {off }}{ }^{6}$ | Turn-Off Switching Energy |  |  | 838 |  |  |

1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
2 Pulse test: Pulse Width < 380 $\mu$ s, duty cycle < 2\%.
3 See Mil-Std-750 Method 3471
$4 R_{G}$ is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
$5 \mathrm{E}_{\text {on2 }}$ is the clamped inductive turn on energy that includes a commutating diode reverse recovery current in the IGBT turn on energy loss. A combi device is used for the clamping diode.
$6 E_{\text {off }}$ is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1
Microsemi reserves the right to change, without notice, the specifications and information contained herein.

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FIGURE 3, Transfer Characteristics


FIGURE 5, On State Voltage vs Gate-to-Emitter Voltage


FIGURE 7, Threshold Voltage vs Junction Temperature



FIGURE 4, Gate charge


FIGURE 6, On State Voltage vs Junction Temperature


FIGURE 8, DC Collector Current vs Case Temperature

Typical Performance Curves


FIGURE 9, Turn-On Delay Time vs Collector Current


FIGURE 11, Current Rise Time vs Collector Current


FIGURE 13, Turn-On Energy Loss vs Collector Current

FIGURE 15, Switching Energy Losses vs Gate Resistance

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FIGURE 10, Turn-Off Delay Time vs Collector Current


FIGURE 12, Current Fall Time vs Collector Current


FIGURE 14, Turn-Off Energy Loss vs Collector Current


FIGURE 16, Switching Energy Losses vs Junction Temperature


FIGURE 17，Capacitance vs Collector－To－Emitter Voltage



Figure 19，Maximum Effective Transient Thermal Impedance，Junction－To－Case vs Pulse Duration


Figure 12, Inductive Switching Test Circuit


Figure 14, Turn-off Switching Waveforms and Definitions


Figure 13, Turn-on Switching Waveforms and Definitions

TO-247 Package Outline
(e1) SAC: Tin, Silver, Copper

D3PAK Package Outline
(e3) $100 \%$ Sn Plated


Dimensions in Millimeters (Inches)

